

Supplementary Information for Layer-resolving ability and model analysis of LIBS for multilayer samples with a four-layer structure under different focusing conditions (Part 3 of 3)

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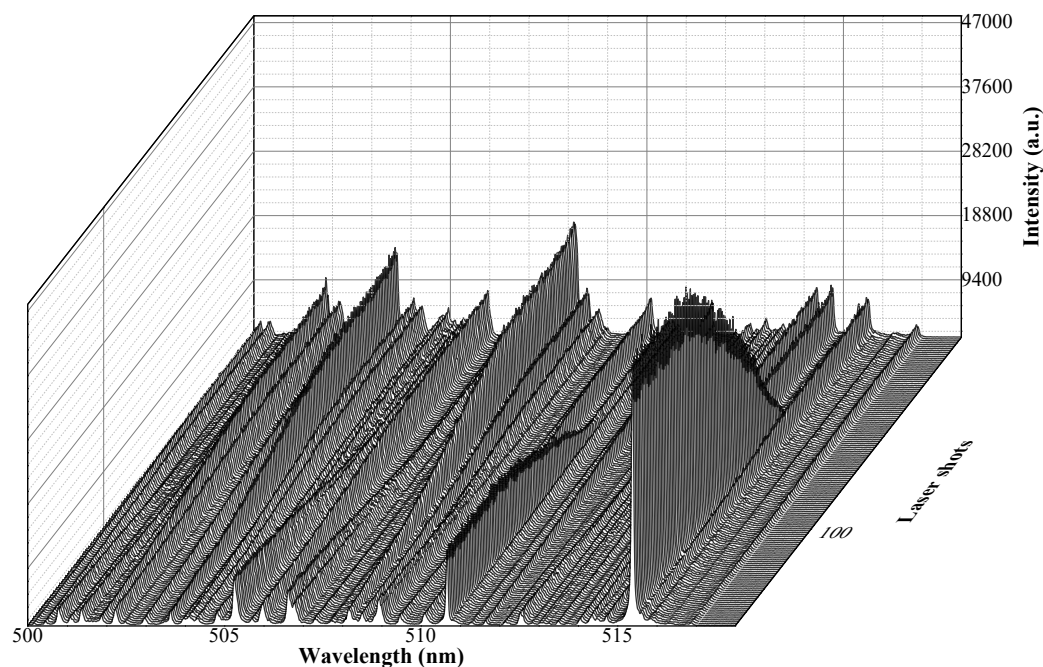


Figure. S11. Typical spectra of sample S3 at $\Delta L = 9$ cm.

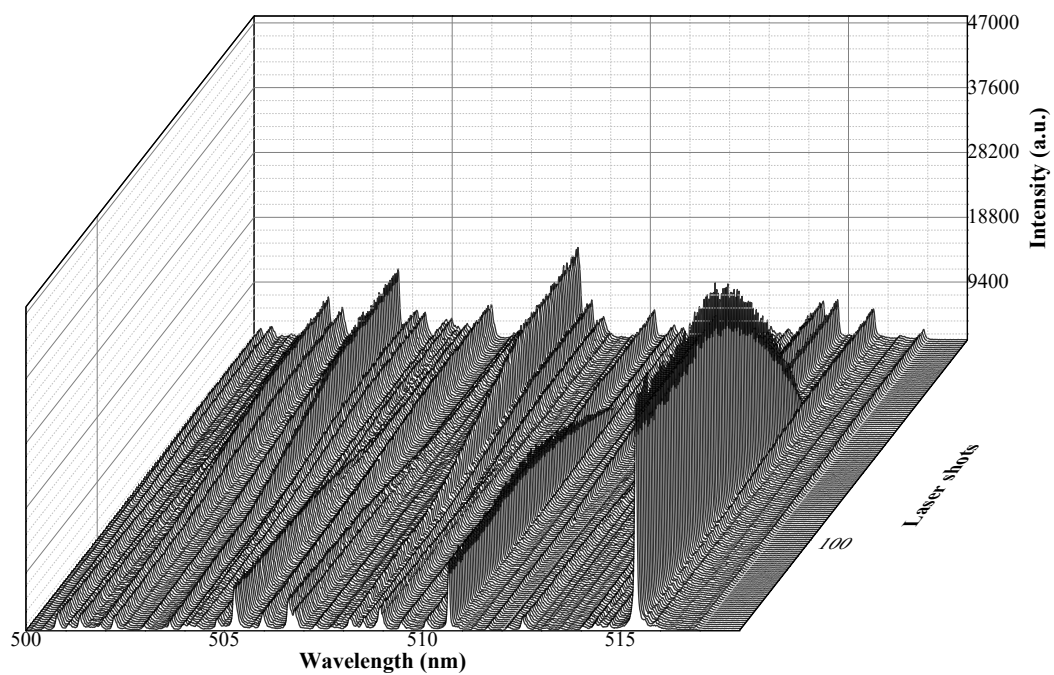


Figure. S12. Typical spectra of sample S3 at $\Delta L = 8$ cm.

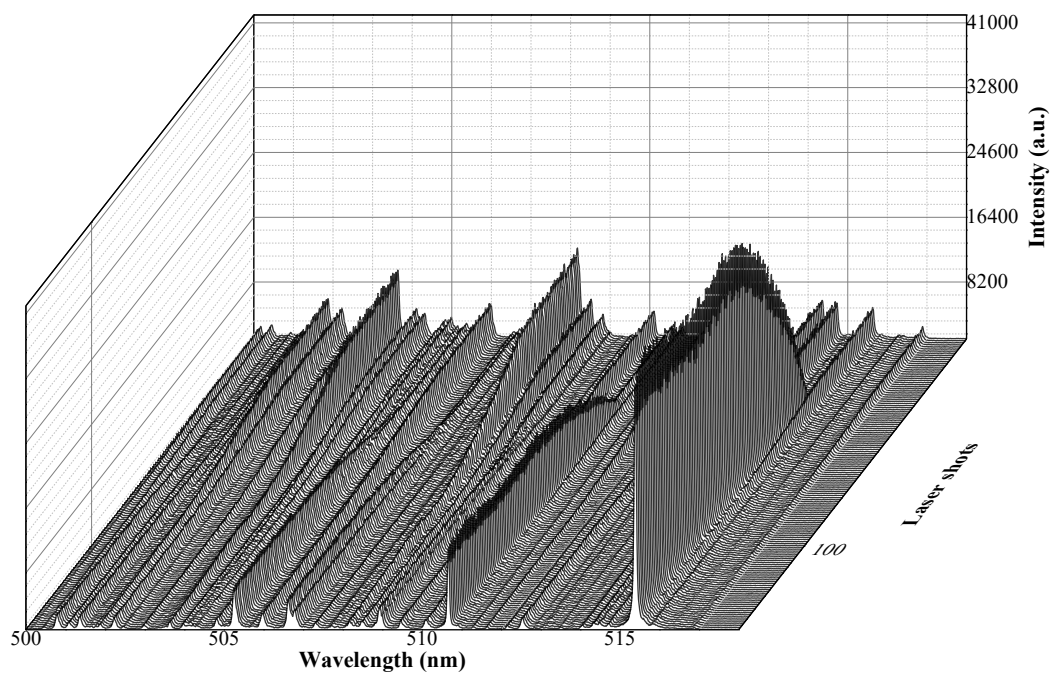


Figure. S13. Typical spectra of sample S3 at $\Delta L = 7$ cm.

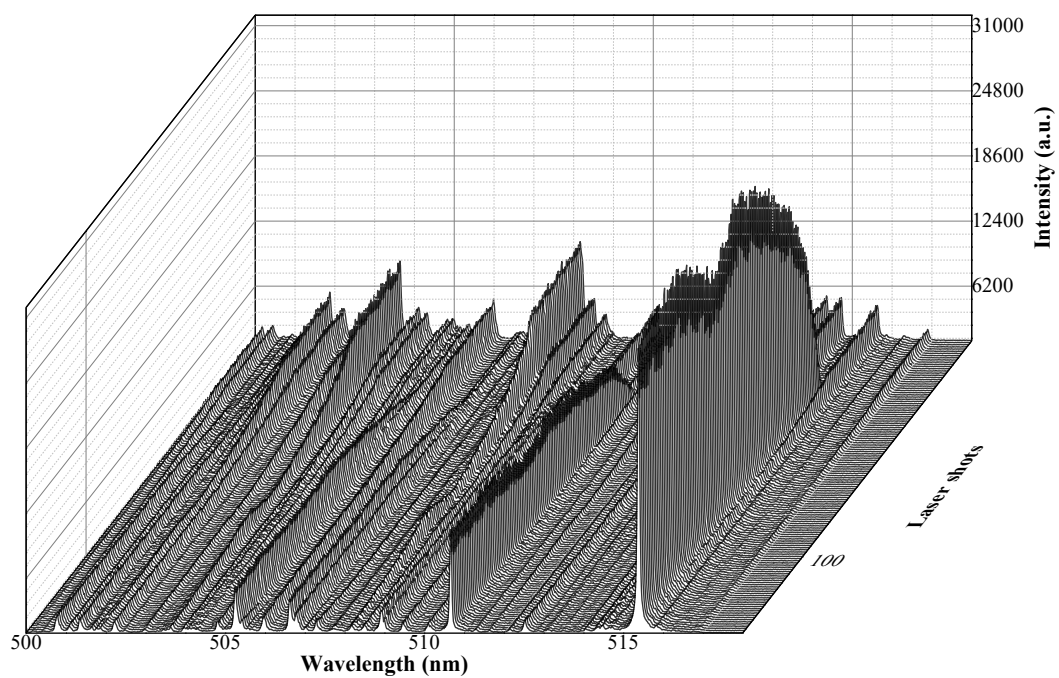


Figure. S14. Typical spectra of sample S3 at $\Delta L = 6$ cm.

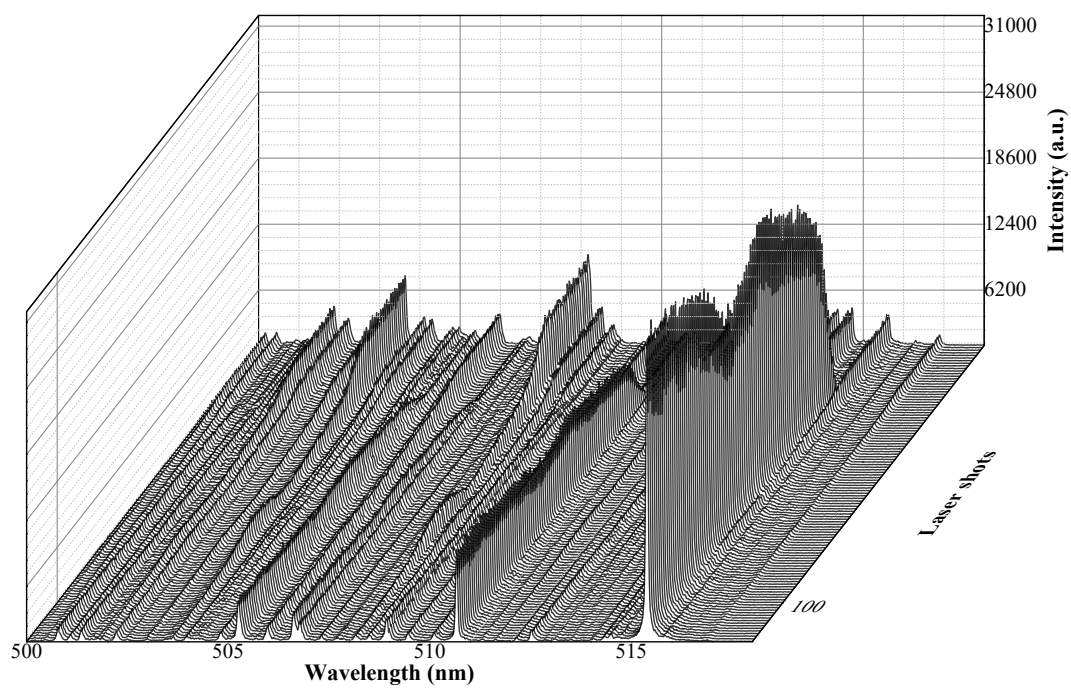


Figure. S15. Typical spectra of sample S3 at $\Delta L = 5$ cm.